# **MOSFET** – Power, N-Channel, **SUPERFET III, Easy Drive**

# 650 V, 14 A, 199 mΩ

#### Description

SUPERFET III MOSFET is ON Semiconductor's brand-new high voltage super-junction (SJ) MOSFET family that is utilizing charge balance technology for outstanding low on-resistance and lower gate charge performance. This advance technology is tailored to minimize conduction loss, provide superior switching performance, and withstand extreme dv/dt rate. Consequently, SUPERFET III MOSFET is very suitable for various power system miniaturization and higher efficiency.

# **Features**

- $700 \text{ V} @ \text{T}_{\text{J}} = 150^{\circ}\text{C}$
- Typ.  $R_{DS(on)} = 170 \text{ m}\Omega$
- Ultra Low Gate Charge (Typ. Q<sub>g</sub> = 30 nC)
- Low Effective Output Capacitance (Typ. C<sub>oss(eff.)</sub> = 277 pF)
- 100% Avalanche Tested
- These Devices are Pb-Free and are RoHS Compliant

#### **Applications**

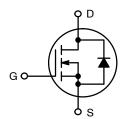
- Telecom / Server Power Supplies
- Industrial Power Supplies
- UPS / Solar



#### ON Semiconductor®

#### www.onsemi.com

V <sub>DSS</sub>	R <sub>DS(ON)</sub> MAX	I <sub>D</sub> MAX
650 V	199 mΩ @ 10 V	14 A



**POWER MOSFET** 



D2-PAK CASE 418AJ

#### MARKING DIAGRAM



\$Y = ON Semiconductor Logo &Z = Assembly Plant Code &3 = Data Code (Year & Week)

&K

FCB199N65S3 = Specific Device Code

#### ORDERING INFORMATION

See detailed ordering and shipping information on page 2 of this data sheet.

# ABSOLUTE MAXIMUM RATINGS (T<sub>C</sub> = 25°C, Unless otherwise specified)

Symbol	Parame	Value	Unit		
$V_{DSS}$	Drain to Source Voltage	650	V		
$V_{GSS}$	Gate to Source Voltage	DC	±30	V	
		AC (f > 1 Hz)	±30	V	
I <sub>D</sub>	Drain Current	Continuous (T <sub>C</sub> = 25°C)	14	Α	
		Continuous (T <sub>C</sub> = 100°C)	9		
I <sub>DM</sub>	Drain Current	Pulsed (Note 1)	35	Α	
E <sub>AS</sub>	Single Pulsed Avalanche Energy (Note 2)		76	mJ	
I <sub>AS</sub>	Avalanche Current (Note 1)		2.5	Α	
E <sub>AR</sub>	Repetitive Avalanche Energy (Note 1)		0.98	mJ	
dv/dt	MOSFET dv/dt		100	V/ns	
	Peak Diode Recovery dv/dt (Note 3)		20		
$P_{D}$	Power Dissipation	(T <sub>C</sub> = 25°C)	98	W	
		Derate Above 25°C	0.79	W/°C	
T <sub>J</sub> , T <sub>STG</sub>	Operating and Storage Temperature Range		-55 to +150	°C	
TL	Maximum Lead Temperature for Soldering, 1/8" from Case for 5 s		300	°C	

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

- 1. Repetitive rating: pulse-width limited by maximum junction temperature. 
  2.  $I_{AS}=2.5$  A,  $R_{G}=25$   $\Omega$ , starting  $T_{J}=25^{\circ}C$ . 
  3.  $I_{SD}\leq 7$  A, di/dt  $\leq 200$  A/ $\mu$ s,  $V_{DD}\leq 400$  V, starting  $T_{J}=25^{\circ}C$ .

#### THERMAL CHARACTERISTICS

Symbol	Parameter	Value	Unit
$R_{ heta JC}$	Thermal Resistance, Junction to Case, Max.	1.27	°C/W
	Thermal Resistance, Junction to Ambient, Max. (Note 4)	40	

<sup>4.</sup> Device on 1 in<sup>2</sup> pad 2 oz copper pad on 1.5 x 1.5 in. board of FR-4 material.

### PACKAGE MARKING AND ORDERING INFORMATION

Part Number	Top Marking	Package	Reel Size	Tape Width	Shipping <sup>†</sup>
FCB199N65S3	FCB199N65S3	D <sup>2</sup> -PAK	330 mm	24 mm	800 / Tape & Reel

<sup>†</sup>For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specifications Brochure, BRD8011/D.

# **ELECTRICAL CHARACTERISTICS** (T<sub>C</sub> = 25°C unless otherwise noted)

Breakdown Voltage  Breakdown Voltage Temperature Coefficient  Zero Gate Voltage Drain Current  Gate to Body Leakage Current  IISTICS  Gate Threshold Voltage  Static Drain to Source On Resistance Forward Transconductance	$\begin{split} &V_{GS} = 0 \text{ V, } I_D = 1 \text{ mA, } T_J = 25^{\circ}\text{C} \\ &V_{GS} = 0 \text{ V, } I_D = 1 \text{ mA, } T_J = 150^{\circ}\text{C} \\ &I_D = 1 \text{ mA, Referenced to } 25^{\circ}\text{C} \\ &V_{DS} = 650 \text{ V, } V_{GS} = 0 \text{ V} \\ &V_{DS} = 520 \text{ V, } T_C = 125^{\circ}\text{C} \\ &V_{GS} = \pm 30 \text{ V, } V_{DS} = 0 \text{ V} \\ &V_{GS} = 10 \text{ V, } I_D = 0.36 \text{ mA} \\ &V_{GS} = 10 \text{ V, } I_D = 7 \text{ A} \end{split}$	650 700 2.5	0.6	1 ±100	V V V/°C μΑ
Breakdown Voltage Temperature Coefficient  Zero Gate Voltage Drain Current  Gate to Body Leakage Current  ISTICS  Gate Threshold Voltage  Static Drain to Source On Resistance	$V_{GS} = 0 \text{ V, } I_D = 1 \text{ mA, } T_J = 150^{\circ}\text{C}$ $I_D = 1 \text{ mA, } \text{Referenced to } 25^{\circ}\text{C}$ $V_{DS} = 650 \text{ V, } V_{GS} = 0 \text{ V}$ $V_{DS} = 520 \text{ V, } T_C = 125^{\circ}\text{C}$ $V_{GS} = \pm 30 \text{ V, } V_{DS} = 0 \text{ V}$ $V_{GS} = V_{DS}, I_D = 0.36 \text{ mA}$	700			V V/°C μA
Coefficient Zero Gate Voltage Drain Current  Gate to Body Leakage Current  IISTICS  Gate Threshold Voltage  Static Drain to Source On Resistance	$I_{D} = 1 \text{ mA, Referenced to } 25^{\circ}\text{C}$ $V_{DS} = 650 \text{ V}, V_{GS} = 0 \text{ V}$ $V_{DS} = 520 \text{ V}, T_{C} = 125^{\circ}\text{C}$ $V_{GS} = \pm 30 \text{ V}, V_{DS} = 0 \text{ V}$ $V_{GS} = V_{DS}, I_{D} = 0.36 \text{ mA}$				V/°C μA
Coefficient Zero Gate Voltage Drain Current  Gate to Body Leakage Current  IISTICS  Gate Threshold Voltage  Static Drain to Source On Resistance	$V_{DS} = 650 \text{ V}, V_{GS} = 0 \text{ V}$ $V_{DS} = 520 \text{ V}, T_C = 125^{\circ}\text{C}$ $V_{GS} = \pm 30 \text{ V}, V_{DS} = 0 \text{ V}$ $V_{GS} = V_{DS}, I_D = 0.36 \text{ mA}$	2.5			μΑ
Gate to Body Leakage Current  ISTICS  Gate Threshold Voltage  Static Drain to Source On Resistance	$V_{DS}$ = 520 V, $T_{C}$ = 125° C $V_{GS}$ = ±30 V, $V_{DS}$ = 0 V $V_{GS}$ = $V_{DS}$ , $V_{DS}$ = 0.36 mA	2.5	0.89		
Gate Threshold Voltage Static Drain to Source On Resistance	$V_{GS} = \pm 30 \text{ V}, V_{DS} = 0 \text{ V}$ $V_{GS} = V_{DS}, I_{D} = 0.36 \text{ mA}$	2.5	0.89	±100	пA
Gate Threshold Voltage Static Drain to Source On Resistance	$V_{GS} = V_{DS}, I_D = 0.36 \text{ mA}$	2.5		±100	пA
Gate Threshold Voltage Static Drain to Source On Resistance		2.5	1		
Static Drain to Source On Resistance		2.5	1		
	V <sub>GS</sub> = 10 V, I <sub>D</sub> = 7 A			4.5	V
Forward Transconductance			170	199	mΩ
	V <sub>DS</sub> = 20 V, I <sub>D</sub> = 7 A		10		S
ACTERISTICS		•	•		
Input Capacitance	V <sub>DS</sub> = 400 V, V <sub>GS</sub> = 0 V, f = 1 MHz		1225		pF
Output Capacitance			30		pF
Effective Output Capacitance	V <sub>DS</sub> = 0 V to 400 V, V <sub>GS</sub> = 0 V		277		pF
Energy Related Output Capacitance	V <sub>DS</sub> = 0 V to 400 V, V <sub>GS</sub> = 0 V		43		pF
Total Gate Charge at 10 V	$V_{DS} = 400 \text{ V}, I_D = 7 \text{ A}, V_{GS} = 10 \text{ V}$		30		nC
Gate to Source Gate Charge	(Note 5)		7.4		nC
Gate to Drain "Miller" Charge	1		13		nC
Equivalent Series Resistance	f = 1 MHz		7		Ω
RACTERISTICS		•		•	
Turn-On Delay Time	V <sub>DD</sub> = 400 V, I <sub>D</sub> = 7 A,		19		ns
Turn-On Rise Time	V <sub>GS</sub> = 10 V, R <sub>g</sub> = 4.7 Ω (Note 5)		23		ns
Turn-Off Delay Time			52		ns
Turn-Off Fall Time			15		ns
DIODE CHARACTERISTICS					
Maximum Continuous Source to Drain Diode Forward Current				14	Α
Maximum Pulsed Source to Drain Diode Forward Current				35	Α
Source to Drain Diode Forward Voltage	V <sub>GS</sub> = 0 V, I <sub>SD</sub> = 7 A			1.2	V
Reverse Recovery Time	V <sub>DD</sub> = 400 V, I <sub>SD</sub> = 7 A,		256		ns
Reverse Recovery Charge	dI <sub>F</sub> /dt = 100 A/μs		3.5		μC
	ACTERISTICS  Input Capacitance  Dutput Capacitance  Effective Output Capacitance  Energy Related Output Capacitance  Fotal Gate Charge at 10 V  Gate to Source Gate Charge  Gate to Drain "Miller" Charge  Equivalent Series Resistance  RACTERISTICS  Furn-On Delay Time  Furn-Off Delay Time  Furn-Off Fall Time  DIODE CHARACTERISTICS  Maximum Continuous Source to Drain Diode F  Source to Drain Diode Forward Voltage  Reverse Recovery Time	ACTERISTICS  Input Capacitance  Dutput Capacitance  Effective Output Capacitance  Effective Output Capacitance  Floating Related Output Capacitance  Floating Related Output Capacitance  Floating Gate Charge at 10 V  Floating Gate to Drain "Miller" Charge  Floating Gate to Drain Time  Floating Gate Time	ACTERISTICS  Input Capacitance  Cutput Capacitance  Effective Output Capacitance  Energy Related Output Capacitance  Coutput Capacitance  Energy Related Output Capacitance  Coutput Capacitance  Energy Related Output Capacitance  Coutput Capacitance  Coutput Capacitance  VDS = 0 V to 400 V, VGS = 0 V  Coutput Capacitance  VDS = 400 V, VDS = 400 V, VDS = 10 V  (Note 5)  Coutput Capacitance  VDS = 0 V to 400 V, VGS = 0 V  (Note 5)  Coutput Capacitance  VDS = 0 V to 400 V, VDS = 0 V  (Note 5)  Coutput Capacitance  VDS = 0 V to 400 V, VDS = 0 V  (Note 5)  Coutput Capacitance  VDS = 0 V to 400 V, VDS = 0 V  (Note 5)  Coutput Capacitance  VDS = 0 V to 400 V, VDS = 0 V  (Note 5)  Coutput Capacitance  VDS = 0 V to 400 V, VDS = 0 V  (Note 5)  Coutput Capacitance  VDS = 0 V to 400 V, VDS = 1 MHz  (Note 5)  Coutput Capacitance  VDS = 0 V to 400 V, VDS = 1 MHz  (Note 5)  Coutput Capacitance  VDD = 400 V, VD = 7 A, VDS = 10 V  (Note 5)  Coutput Capacitance  VDD = 400 V, VDS = 0 V, VDS = 1 MHz  Coutput Capacitance  VDD = 400 V, VDS = 0 V, VDS = 7 A, VDS = 7 A, VDS = 7 A, VDS = 7 A, VDS = 400 V, VDS = 400 V, VDS = 7 A, VDS = 400 V, VDS = 400 V, VDS = 7 A, VDS = 400 V, VDS = 400 V, VDS = 7 A, VDS = 400 V, VDS = 400 V, VDS = 400 V, VDS = 400 V, VDS = 7 A, VDS = 400 V, VDS = 400 V, VDS = 400 V, VDS = 7 A, VDS = 400 V, VDS = 7 A, VDS = 400 V, VDS	ACTERISTICS   VDS = 400 V, VGS = 0 V, f = 1 MHz   1225     Dutput Capacitance   VDS = 0 V to 400 V, VGS = 0 V   277     Energy Related Output Capacitance   VDS = 0 V to 400 V, VGS = 0 V   43     Interpretation of the properties of the properti	Variable   Variable

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

5. Essentially independent of operating temperature typical characteristics.

#### TYPICAL PERFORMANCE CHARACTERISTICS

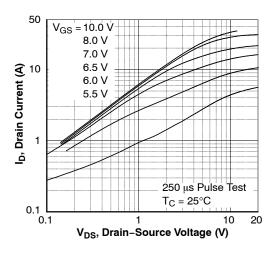


Figure 1. On-Region Characteristics

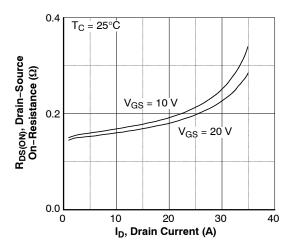


Figure 3. On-Resistance Variation vs.
Drain Current and Gate Voltage

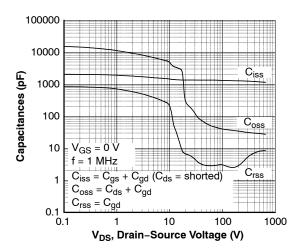


Figure 5. Capacitance Characteristics

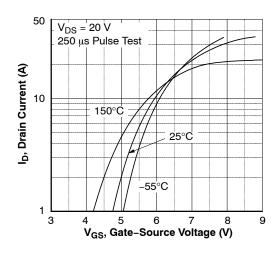


Figure 2. Transfer Characteristics

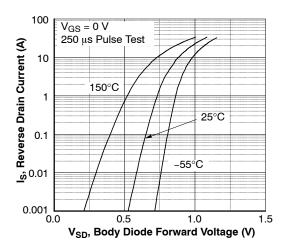


Figure 4. Body Diode Forward Voltage Variation vs. Source Current and Temperature

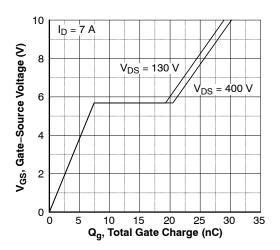


Figure 6. Gate Charge Characteristics

#### TYPICAL PERFORMANCE CHARACTERISTICS (Continued)

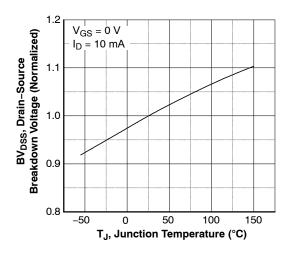


Figure 7. Breakdown Voltage Variation vs. Temperature

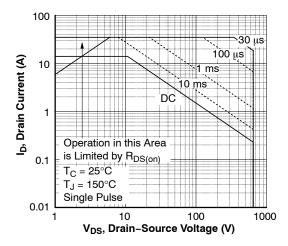


Figure 9. Maximum Safe Operating Area

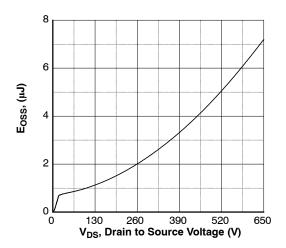


Figure 11.  $E_{\mbox{\scriptsize OSS}}$  vs. Drain to Source Voltage

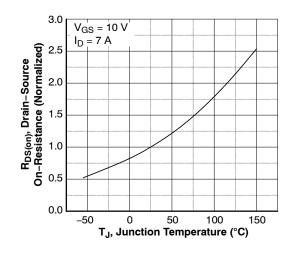


Figure 8. On–Resistance Variation vs. Temperature

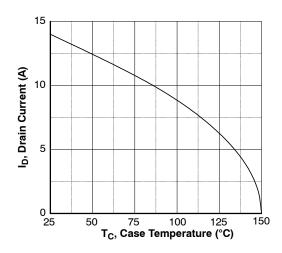


Figure 10. Maximum Drain Current vs. Case Temperature

# TYPICAL PERFORMANCE CHARACTERISTICS (Continued)

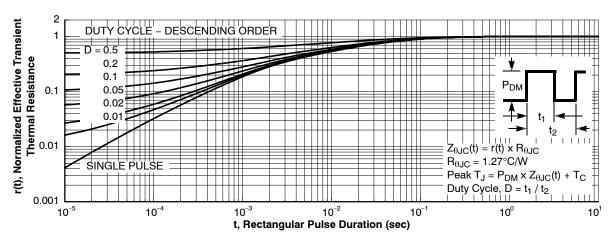


Figure 12. Transient Thermal Response Curve

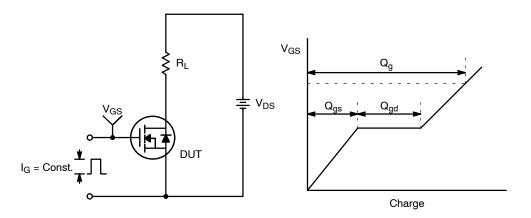


Figure 13. Gate Charge Test Circuit & Waveform

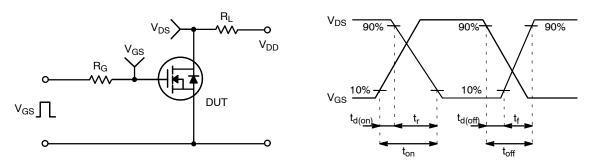


Figure 14. Resistive Switching Test Circuit & Waveforms

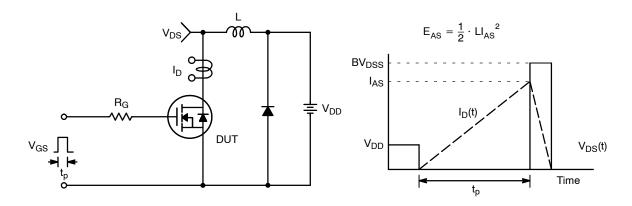


Figure 15. Unclamped Inductive Switching Test Circuit & Waveforms

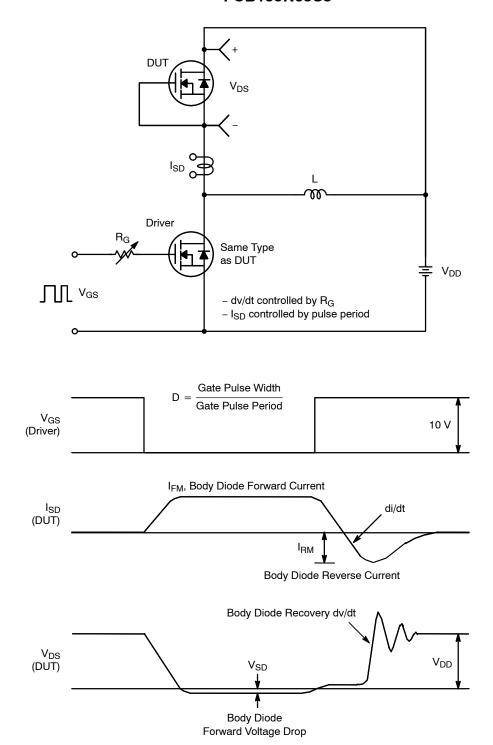


Figure 16. Peak Diode Recovery dv/dt Test Circuit & Waveforms

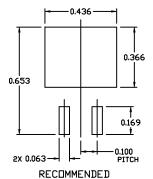
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#### D<sup>2</sup>PAK-3 (TO-263, 3-LEAD) CASE 418AJ ISSUE D

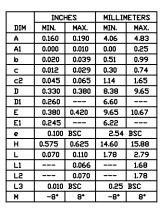
**DATE 13 AUG 2019** 

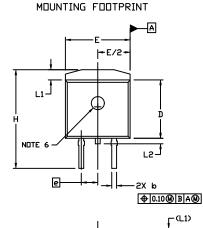
#### SCALE 1:1



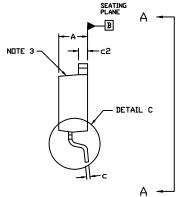
#### NOTES

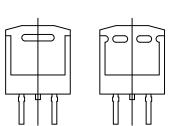
- DIMENSIONING AND TOLERANCING PER ASME Y14.5M, 1994.
- 2. CONTROLLING DIMENSION: INCHES
- 3. CHAMFER OPTIONAL.
- 4. DIMENSIONS D AND E DO NOT INCLUDE MOLD FLASH.
  MOLD FLASH SHALL NOT EXCEED 0.005 PER SIDE.
  THESE DIMENSIONS ARE MEASURED AT THE OUTERMOST
  EXTREMES OF THE PLASTIC BODY AT DATUM H.
- THERMAL PAD CONTOUR IS OPTIONAL WITHIN DIMENSIONS E, L1, D1, AND E1.
- 6. OPTIONAL MOLD FEATURE.



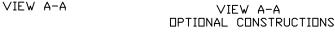


n1



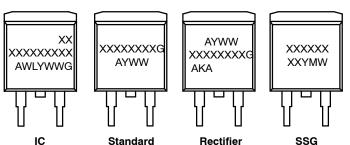


DETAIL C
TIP LEADFORM
ROTATED 90° CW



#### **GENERIC MARKING DIAGRAMS\***

**♦** 0.10 **№** B A **№** 



XXXXXX = Specific Device Code

A = Assembly Location

WL = Wafer Lot
 Y = Year
 WW = Work Week
 W = Week Code (SSG)
 M = Month Code (SSG)
 G = Pb-Free Package
 AKA = Polarity Indicator

\*This information is generic. Please refer to device data sheet for actual part marking. Pb-Free indicator, "G" or microdot " •", may or may not be present. Some products may not follow the Generic Marking.

DOCUMENT NUMBER:

98AON56370E

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**DESCRIPTION:** 

D<sup>2</sup>PAK-3 (TO-263, 3-LEAD)

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